## **Electrical Contact Property and Control Effects for Stable**

## T(H)-TaS<sub>2</sub>/C<sub>3</sub>B Metal-Semiconductor Heterojunction

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## **Supplementary Information**



**Fig. S1** (a) and (b) the band structure of T-TaS2 and H-TaS2 monolayers under different tensile strains, where the largest tensile strains just correspond to fully match the T(H)-TaS2 and H-TaS2 monolayers to the intrinsic C3B monolayer, respectively. (c) and (d) the band structure of C3B under different compressive strains, where the largest compressive strains just correspond to fully match the C3B monolayer to the intrinsic T-TaS2 and H-TaS2, respectively.

Heterojunction	Mismatch rate(%)	Stack configuration	Interlayer distances(Å)	Binding energy(meV/Å <sup>2</sup> )
		$A_1$	3.32	-45.64
T-TaS <sub>2</sub> /C <sub>3</sub> B	1.90	$A_2$	3.33	-44.89
		A <sub>3</sub>	3.33	-44.89
		A4	3.34	-44.88
		$\mathbf{B}_1$	3.33	-43.62
H-TaS <sub>2</sub> /C <sub>3</sub> B	3.09	$B_2$	3.33	-43.62
		<b>B</b> <sub>3</sub>	3.33	-43.63
		$B_4$	3.33	-43.62

Table S1 Mismatch rate, interlayer distance, and binding energy for various stack configurations.

**Table S2** Tunnel barrier height ( $\Phi_{TB}$ ), half width of the tunneling barrier( $W_{TB}$ ), tunneling probability ( $T_{TB}$ ) and comprehensive factor (C) of heterojunctions

	$W_{TB}(\text{\AA})$	$\Phi_{TB}(eV)$	$T_{TB}(\%)$	C(eVÅ <sup>-2</sup> )
T-TaS <sub>2</sub> /C <sub>3</sub> B	1.28	19.17	2.58%	31.40
H-TaS <sub>2</sub> /C <sub>3</sub> B	1.22	17.56	3.57%	26.14



Fig. S2 Fig. S2 Projected band structure for heterojunctions by HSE06 calculations: (a)  $T-TaS_2/C_3B$ , (b)  $H-TaS_2/C_3B$ , where red, blue and purple represent the projected band structure of the  $C_3B$ ,  $T-TaS_2$ , and  $H-TaS_2$  monolayer, respectively.

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